ALTERNATION HISTORY RECORDS 变更记录

Date 日期	Version 版本	Mark 标记	Page 页码	Description 描述	Drafter 制定者	Approver 审批者
2022-02-18	B	/	17	Version change	常斯琴	彭旭

1. DESCRIPTION

Soft Termination Chip Multilayer Ceramic Capacitors for Automotive is designed and with a polymer layer within end terminations of product, which can absorb mechanical stress caused by PCB handling in SMT line and reduce the mechanical impact for product. It will offer more robust and reliable performance in applications.

ST series MLCC is made by X7R dielectric and which provides product with high electrical precision, stability and reliability. Besides, ST series MLCC is tighten controlling in quality in line to assure quality performance in automotive applications. The ST series is AEC-Q200 compliant.

2. FEATURES

a. MLCC's terminations are with a soft & flexible polymer layer to withstand high bending stress in SMT line.
b. High reliability: AEC-Q200.

3. APPLICATIONS

a. Automotive, power supply and related industries. .
b. The other mechanical stress concerned products or the set having a high probability of fall.
c. Prevention of ceramic body cracks by board bending.

4. HOW TO ORDER

ST	0603	B	104	F	500	X	D
Series	**Size**	**Dielectric**	**Capacitance**	**Tolerance**	**Rated voltage**	**Thickness**	**Packing Q'TY**
ST=Soft Termination MLCC for Automotive (ST series) Qualified to AEC-Q200	0603 (1608) 0805 (2012) 1206 (3216) 1210 (3225)	**B**=X7R	Two significant digits followed by no. of zeros. And R is in place of decimal point. Eg. 104=10x10^4 =100nF	**A**=±0.05pF **B**=±0.1pF **C**=±0.25pF **D**=±0.5pF **F**=±1% **G**=±2% **J**=±5%	Two significant digits followed by no. of zeros. And R is in place of decimal point. **6R3**=6.3 VDC **100**=10 VDC **160**=16 VDC **250**=25 VDC **500**=50 VDC **101**=100 VDC	Refer Item 5&7	A:1K/Reel B:2K/Reel C:3K/Reel D:4K/Reel I:10K/Reel

5. EXTERNAL DIMENSIONS

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Symbol		Remark	M_B (mm)
0603 (1608)	1.60±0.20	0.80±0.10	0.80±0.07	S		0.40±0.15
	1.60±0.30	0.80±0.30	0.80±0.30	X		
0805 (2012)	2.00±0.20	1.25±0.10	1.25±0.10	D	#	0.50±0.20
1210 (3225)	3.20±0.60	2.50±0.50	2.50±0.50	M	#	0.75±0.25

Reflow soldering only is recommended.

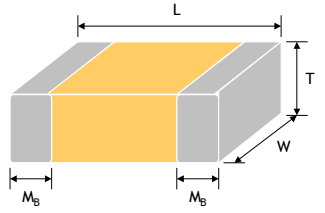

Fig. 1 The outline of MLCC

6. GENERAL ELECTRICAL DATA

Dielectric	X7R
Size	0603, 0805, 1210
Capacitance range*	1000pF to 2.2μF
Capacitance tolerance**	J (±5%), K (±10%), M (±20%)
Rated voltage (WVDC)	10V, 16V, 25V, 50V, 100V
Operating temperature	-55 to +125℃
Capacitance characteristic	±15%
Termination	Ni/Sn (lead-free termination)

* Measured at the condition of 30~70% related humidity.
Measured at 1.0±0.2Vrms, 30~70% related humidity, 25℃ ambient temperature for X7R.
** Preconditioning for Class II MLCC: Perform a heat treatment at 150±10℃ for 1 hour, then leave in a mbient condition for 24±2 hours before measurement.

7. CAPACITANCE RANGE

DIELECTRIC		X7R								
SIZE		0603				0805				1210
RATED VOLTAGE (VDC)		10	16	25	50	10	16	25	50	100
Capacitance	1,000pF (102)	S	S	S	S	D	D	D	D	
	1,200pF (122)	S	S	S	S	D	D	D	D	
	1,500pF (152)	S	S	S	S	D	D	D	D	
	1,800pF (182)	S	S	S	S	D	D	D	D	
	2,200pF (222)	S	S	S	S	D	D	D	D	
	2,700pF (272)	S	S	S	S	D	D	D	D	
	3,300pF (332)	S	S	S	S	D	D	D	D	
	3,900pF (392)	S	S	S	S	D	D	D	D	
	4,700pF (472)	S	S	S	S	D	D	D	D	
	5,600pF (562)	S	S	S	S	D	D	D	D	
	6,800pF (682)	S	S	S	S	D	D	D	D	
	8,200pF (822)	S	S	S	S	D	D	D	D	
	0.010μF (103)	S	S	S	S	D	D	D	D	
	0.012μF (123)	S	S	S	S	D	D	D	D	
	0.015μF (153)	S	S	S	S	D	D	D	D	
	0.018μF (183)	S	S	S	S	D	D	D	D	
	0.022μF (223)	S	S	S	S	D	D	D	D	
	0.027μF (273)	S	S	S	S	D	D	D	D	
	0.033μF (333)	S	S	S	X	D	D	D	D	
	0.039μF (393)	S	S	S	X	D	D	D	D	
	0.047μF (473)	S	S	S	X	D	D	D	D	
	0.056μF (563)	S	S	S	X	D	D	D	D	
	0.068μF (683)	S	S	S	X	D	D	D	D	
	0.082μF (823)	S	S	S	X	D	D	D	D	
	0.10μF (104)	S	S	S	X	D	D	D	D	
	0.12μF (124)	X	X	X						
	0.15μF (154)	X	X	X						
	0.18μF (184)	X	X	X						
	0.22μF (224)	X	X	X						
	2.2μF (225)									M

1. The letter in cell is expressed the symbol of product thickness.
2. For more information about products with special capacitance or other data, please contact local representative.

8. PACKAGING STYLE AND QUANTITY

Size	Thickness (mm)/Symbol		Paper tape		Plastic tape	
			7" reel	13" reel	7" reel	13" reel
0603 (1608)	0.80±0.07	S	4k	15k	-	-
	0.80±0.30	X	4k	15k	-	-
0805 (2012)	1.25±0.10	D	-	-	3k	10k
1210 (3225)	2.50±0.50	M	-	-	1k	6k

Unit: pieces

9. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

<table>
<tr><th>No.</th><th>AEC-Q200 Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>1.</td><td>Pre-and Post-Stress Electrical Test</td><td>---</td><td></td></tr>
<tr><td>2.</td><td>High Temperature Exposure (Storage)
MIL-STD-202
Method 108</td><td>* Test temp.: 150±3℃
* Unpowered.
* Test time: 1000+24/-0 hrs.
* Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>* No remarkable damage.
* Cap change：NPO: within ±2.5% or ±0.25pF whichever is larger.
X7R: within ±10.00%.
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th>Exception of D.F.≦</th><th></th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦7.5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦20%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>0201(50V);0603≧0.047μF;0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.01uF;1210≧3.3μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.012μF;0603>0.1μF; 0805/X7R>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦5%</td><td>≦20%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦5%</td><td>≦10%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦14%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0603≧0.15μF;0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.022μF;0402≧0.033μF;
0603>0.47μF;0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦7.5%</td><td>≦15%</td><td>0201≧0.012μF;0402≧0.22μF;
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<tr><td>≦20%</td><td>0201≧0.1μF;0402≧1μF</td></tr>
<tr><td>6.3V</td><td>≦15%</td><td>≦30%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF;1206≧47μF;1210≧100μF</td></tr>
<tr><td>4V</td><td>≦20%</td><td>---</td><td>---</td></tr>
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* I.R.: ≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="6">1GΩ or RxC≧10 Ω-F whichever is smaller.</td></tr>
<tr><td>50V: 0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
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<tr><td>25V:0201≧0.1uF; 0402≥0.22μF; 0603≥2.2μF;0805≥2.2μF;
1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≧0.1uF;0402≥0.22μF;0603≥1μF;0805≥2.2μF;
1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
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* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

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<tr><td>3.</td><td>Temperature Cycling
JESD22
Method JA-104</td><td>
* Conduct 1000 cycles according to the temperatures and time.
<table>
<tr><th>Step</th><th>Temp. (℃)</th><th>Time (min.)</th></tr>
<tr><td>1</td><td>-55℃ +0/-3</td><td>5±1</td></tr>
<tr><td>2</td><td>+125℃ +3/-0</td><td>5±1</td></tr>
</table>
* Before initial measurement (X7R only):
Perform 150+0/-10℃ for 1 hr and then set for 24±2 hrs at room temp.
*Measurement to be made after keeping at room temp.
for 24±2 hrs.
</td><td>
* No remarkable damage.
* Cap change：NPO: within ±2.5% or 0.25pF whichever is larger.
X7R: within ±10.0%.
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
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* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

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Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>4.</td><td>Destructive
Physical Analysis
EIA-469</td><td>Per EIA-469</td><td>No defects or abnormalities</td></tr>
<tr><td>5.</td><td>Moisture
Resistance
MIL-STD-202
Method 106</td><td>* Test temp.: 25~65℃
* Humidity: 80~100% RH
* Test time: 10 cycles, t=24hrs/cycle.
* Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>* No remarkable damage.
* Cap change : NPO: within ±3.0% or 0.30pF whichever is larger
X7R: within ±12.5%.
* Q/D.F. value:
NPO: More than 30pF Q≥350 ; 10pF≤C≤30pF, Q≥275+2.5C
Less than 10pF Q≥200+10C
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F.≦</th></tr>
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<tr><td rowspan="3">50V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>0201(50V);0603≧0.047μF;0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.01uF;1210≧3.3μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.012μF;0603>0.1μF; 0805/X7R>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
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Class II (X7R)
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<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">1GΩ or RxC≧10 Ω-F whichever is smaller.</td></tr>
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<tr><td>6.</td><td>Biased Humidity
MIL-STD-202
Method 103</td><td>* Test temp.: 85±3℃
* Humidity: 85%RH
* Test time: 1000+24/-0 hrs.
* To apply voltage：rated voltage and 1.3~1.5Vdc.
(add 100k ohm resistor)
* Before initial measurement (Class II only) : To apply test voltage for 1hr at test temp. and then set for 24±2 hrs at room temp.
* Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>* No remarkable damage.
* Cap change: NPO: within ±3.0% or 0.30pF whichever is larger.
X7R: within ±12.5%
* Q/D.F. value:
NPO: C≥30pF , Q≥200 ; C<30pF , Q≥100+10/3C
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F.≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦7.5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦20%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>0201(50V);0603≧0.047μF;0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.01uF;1210≧3.3μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.012μF;0603>0.1μF; 0805/X7R>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦5%</td><td>≦20%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦5%</td><td>≦10%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦14%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0603≧0.15μF;0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.022μF;0402≧0.033μF;
0603>0.47μF;0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦7.5%</td><td>≦15%</td><td>0201≧0.012μF;0402≧0.22μF;
0603≧0.33μF;0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦20%</td><td>0201≧0.1μF;0402≧1μF</td></tr>
<tr><td>6.3V</td><td>≦15%</td><td>≦30%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF;1206≧47μF;1210≧100μF</td></tr>
<tr><td>4V</td><td>≦20%</td><td>---</td><td>---</td></tr>
</table>
* I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.
Class II (X7R) for rated voltage test
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">500MΩ or RxC≧5 Ω-F whichever is smaller.</td></tr>
<tr><td>50V: 0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0603≥1μF;0805≥2.2μF; 1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0201≧0.1uF; 0402≥0.22μF; 0603≥2.2μF;0805≥2.2μF;
1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≧0.1uF;0402≥0.22μF;0603≥1μF;0805≥2.2μF;
1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
</table>
Class II (X7R) for 1.3~1.5Vdc
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">1GΩ or RxC≧10 Ω-F whichever is smaller.</td></tr>
<tr><td>50V: 0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0603≥1μF;0805≥2.2μF; 1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0201≧0.1uF; 0402≥0.22μF; 0603≥2.2μF;0805≥2.2μF;
1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≧0.1uF;0402≥0.22μF;0603≥1μF;0805≥2.2μF;
1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
</table>
</td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200
Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>7.</td><td>Operational Life
MIL-STD-202
Method 108</td><td>* Test temp.: 125±3℃
* To apply voltage: full rated voltage.
* Test time: 1000+24/-0 hrs.
* Before initial measurement (X7R only):
Apply rated voltage for 1 hr at 125℃.
Remove and let set for 24±2 hrs at room temp.
* Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>* No remarkable damage.
* Cap change: NPO: within ±3.0% or ±0.3pF whichever is larger
X7R: within ±12.5%.
* Q/D.F. value:
NPO: More than 30pF, Q≥350 ; 10pF≤C<30pF, Q≥275+2.5C
Less than 10pF, Q≥200+10C
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F.≦</th></tr>
<tr><td rowspan="3">≧ 100V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦7.5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦20%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>0201(50V);0603≧0.047μF;0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.01uF;1210≧3.3μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.012μF;0603>0.1μF; 0805/X7R>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦5%</td><td>≦20%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦5%</td><td>≦10%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦14%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0603≧0.15μF;0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.022μF;0402≧0.033μF;
0603>0.47μF;0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦7.5%</td><td>≦15%</td><td>0201≧0.012μF;0402≧0.22μF;
0603≧0.33μF;0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦20%</td><td>0201≧0.1μF;0402≧1μF</td></tr>
<tr><td>6.3V</td><td>≦15%</td><td>≦30%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF;1206≧47μF;1210≧100μF</td></tr>
<tr><td>4V</td><td>≦20%</td><td>---</td><td>---</td></tr>
</table>
* I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">1GΩ or RxC≧10 Ω-F whichever is smaller.</td></tr>
<tr><td>50V: 0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0603≥1μF;0805≥2.2μF; 1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0201≧0.1uF; 0402≥0.22μF; 0603≥2.2μF;0805≥2.2μF;
1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≧0.1uF;0402≥0.22μF;0603≥1μF;0805≥2.2μF;
1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
</table></td></tr>
<tr><td>8.</td><td>External Visual
MIL-STD-883
Method 2009</td><td>Visual inspection</td><td>No remarkable defect.</td></tr>
<tr><td>9.</td><td>Physical Dimension
JESD22
Method JB-100</td><td>Using by calipers</td><td>Within the specified dimensions</td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200 Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>10.</td><td>Resistance to Solvents
MIL-STD-202
Method 215</td><td>* Temperature: 25±5℃
* Time: 3+0.5/-0 min.
* Solvent: Iso-propyl alcohol.</td><td>* No remarkable damage.
* Cap.: within the specified tolerance.
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F. ≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦10%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>0201(50V); 0603≧0.047μF; 0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0201≧0.01uF; 1210≧3.3μF</td></tr>
<tr><td>≦10%</td><td>0402≧0.012μF;0603>0.1μF; 0805>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦3.5%</td><td>≦10%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦7%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF; 1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td>≦12.5%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0402≧0.033μF;0603≧0.15μF;
0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.022μF; 0402≧ 0.22uF;0603>0.47μF;
0805≧2.2μF;1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0201≧0.012μF;0402≧0.22μF;0603≧0.33μF;
0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧1μF</td></tr>
<tr><td rowspan="2">6.3V</td><td rowspan="2">≦10%</td><td>≦15%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF; 1206≧47μF :1210≧100μF</td></tr>
<tr><td>≦20%</td><td>0402≧2.2μF</td></tr>
<tr><td>4V</td><td>≦15%</td><td>---</td><td>---</td></tr>
</table>
* I.R.: ≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="6">10GΩ or RxC≥100 Ω-F whichever is smaller.</td></tr>
<tr><td>50V:0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0402≥1μF;0603≥2.2μF;0805≥2.2μF;1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≥0.1μF,0402≥0.22μF;0603≥1μF;
0805≥2.2μF;1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V : 4V</td><td rowspan="9">RxC≥50 Ω-F.</td></tr>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: 1210≥3.3μF</td></tr>
<tr><td>50V: 0402≥0.1μF; 0603≥2.2μF; 0805≥10μF;1206≥10μF</td></tr>
<tr><td>35V: 0603≥1μF;</td></tr>
<tr><td>25V: 0201≥0.1μF; 0402≥2.2μF;0603≥10μF; 0805≥10μF;1206≥22μF</td></tr>
<tr><td>16V: 0603≥10μF; 0402≥1μF; 0201≥0.22μF</td></tr>
<tr><td>10V: 0201>0.1μF; 0402≥1μF; 0603≥10μF; 0805≥47μF</td></tr>
<tr><td>6.3V:0201≥0.1μF;0402≥1μF;0603>4.7μF;0805≥47μF;1206≥10μF</td></tr>
<tr><td>4V:0603≥22μF; 0805≥47μF; 1206≥100μF</td></tr>
</table></td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200
Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>11.</td><td>Mechanical Shock
MIL-STD-202
Method 213</td><td>* Peak value: 1500g's.
* Wave: 1/2 sine.
* Velocity: 15.4 ft/sec
* Three shocks in each direction should be applied along
3 mutually perpendicular axes of the test specimen
(18 shocks)</td><td>* No remarkable damage.
* Cap.: within the specified tolerance.
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F. ≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦10%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>0201(50V); 0603≧0.047μF; 0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0201≧0.01uF; 1210≧3.3μF</td></tr>
<tr><td>≦10%</td><td>0402≧0.012μF;0603>0.1μF; 0805>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦3.5%</td><td>≦10%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦7%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF; 1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td>≦12.5%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0402≧0.033μF;0603≧0.15μF;
0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.022μF; 0402≧ 0.22uF;0603>0.47μF;
0805≧2.2μF;1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0201≧0.012μF;0402≧0.22μF;0603≧0.33μF;
0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧1μF</td></tr>
<tr><td rowspan="2">6.3V</td><td rowspan="2">≦10%</td><td>≦15%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF; 1206≧47μF :1210≧100μF</td></tr>
<tr><td>≦20%</td><td>0402≧2.2μF</td></tr>
<tr><td>4V</td><td>≦15%</td><td>---</td><td>---</td></tr>
</table>
* I.R.: ≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">10GΩ or RxC≥100 Ω-F whichever is smaller.</td></tr>
<tr><td>50V:0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0402≥1μF;0603≥2.2μF;0805≥2.2μF;1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≥0.1μF,0402≥0.22μF;0603≥1μF;
0805≥2.2μF;1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
</table>
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: 1210≥3.3μF</td><td rowspan="8">RxC≥50 Ω-F.</td></tr>
<tr><td>50V: 0402≥0.1μF; 0603≥2.2μF; 0805≥10μF;1206≥10μF</td></tr>
<tr><td>35V: 0603≥1μF;</td></tr>
<tr><td>25V: 0201≥0.1μF; 0402≥2.2μF;0603≥10μF; 0805≥10μF;1206≥22μF</td></tr>
<tr><td>16V: 0603≥10μF; 0402≥1μF; 0201≥0.22μF</td></tr>
<tr><td>10V: 0201>0.1μF; 0402≥1μF; 0603≥10μF; 0805≥47μF</td></tr>
<tr><td>6.3V:0201≥0.1μF;0402≥1μF;0603>4.7μF;0805≥47μF;1206≥10μF</td></tr>
<tr><td>4V:0603≥22μF; 0805≥47μF; 1206≥100μF</td></tr>
</table></td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200 Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>12.</td><td>Vibration
MIL-STD-202
Method 204</td><td>* Vibration frequency: 10~2000 Hz/min.
(5g's for 20 min)
* Total amplitude: 1.5mm
* 12 cycles each of 3 orientations (36 times)</td><td>* No remarkable damage.
* Cap.: within the specified tolerance.
* Q/D.F. value:
NPO:Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F. ≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦10%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>0201(50V); 0603≧0.047μF; 0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0201≧0.01uF; 1210≧3.3μF</td></tr>
<tr><td>≦10%</td><td>0402≧0.012μF;0603>0.1μF; 0805>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦3.5%</td><td>≦10%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦7%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF; 1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td>≦12.5%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦3.5%</td><td>≦5%</td><td>0.01μF;0402≧0.033μF;0603≧0.15μF;
≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.022μF; 0402≧ 0.22uF;0603>0.47μF;
0805≧2.2μF;1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0201≧0.012μF;0402≧0.22μF;0603≧0.33μF;
0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧1μF</td></tr>
<tr><td rowspan="2">6.3V</td><td rowspan="2">≦10%</td><td>≦15%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF; 1206≧47μF :1210≧100μF</td></tr>
<tr><td>≦20%</td><td>0402≧2.2μF</td></tr>
<tr><td>4V</td><td>≦15%</td><td>---</td><td>---</td></tr>
</table>
* I.R.:≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="6">10GΩ or RxC≥100 Ω-F whichever is smaller.</td></tr>
<tr><td>50V:0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0402≥1μF;0603≥2.2μF;0805≥2.2μF;1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≥0.1μF,0402≥0.22μF;0603≥1μF;
0805≥2.2μF;1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td><td rowspan="9">RxC≥50 Ω-F.</td></tr>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: 1210≥3.3μF</td></tr>
<tr><td>50V: 0402≥0.1μF; 0603≥2.2μF; 0805≥10μF;1206≥10μF</td></tr>
<tr><td>35V: 0603≥1μF;</td></tr>
<tr><td>25V: 0201≥0.1μF; 0402≥2.2μF;0603≥10μF; 0805≥10μF;1206≥22μF</td></tr>
<tr><td>16V: 0603≥10μF; 0402≥1μF; 0201≥0.22μF</td></tr>
<tr><td>10V: 0201>0.1μF; 0402≥1μF; 0603≥10μF; 0805≥47μF</td></tr>
<tr><td>6.3V:0201≥0.1μF;0402≥1μF;0603>4.7μF;0805≥47μF;1206≥10μF</td></tr>
<tr><td>4V:0603≥22μF; 0805≥47μF; 1206≥100μF</td></tr>
</table></td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200 Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>13.</td><td>Resistance to Soldering Heat
MIL-STD-202
Method 210</td><td>* Solder temperature: 270±5℃
* Dipping time: 10±1 sec
* Before initial measurement (X7R only): Perform 150+0/-10℃ for 1 hr and then set for 24±2 hrs at room temp.
* Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>* No remarkable damage.
* Cap change: NPO: within ±2.5% or 0.25pF whichever is larger
X7R: within ±7.5%
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th>Exception of D.F. ≦</th><th></th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦10%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>0201(50V); 0603≧0.047μF; 0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0201≧0.01uF; 1210≧3.3μF</td></tr>
<tr><td>≦10%</td><td>0402≧0.012μF;0603>0.1μF; 0805>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦3.5%</td><td>≦10%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦7%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF; 1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td>≦12.5%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0402≧0.033μF;0603≧0.15μF;
0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.022μF; 0402≧ 0.22uF;0603>0.47μF;
0805≧2.2μF;1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0201≧0.012μF;0402≧0.22μF;0603≧0.33μF;
0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧1μF</td></tr>
<tr><td>6.3V</td><td>≦10%</td><td>≦15%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF; 1206≧47μF :1210≧100μF</td></tr>
<tr><td rowspan="2">4V</td><td rowspan="2">≦15%</td><td>≦20%</td><td>0402≧2.2μF</td></tr>
<tr><td>---</td><td>---</td></tr>
</table>
* I.R.: ≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">10GΩ or RxC≥100 Ω-F whichever is smaller.</td></tr>
<tr><td>50V:0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0402≥1μF;0603≥2.2μF;0805≥2.2μF;1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≥0.1μF,0402≥0.22μF;0603≥1μF;
0805≥2.2μF;1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: 1210≥3.3μF</td><td rowspan="8">RxC≥50 Ω-F.</td></tr>
<tr><td>50V: 0402≥0.1μF; 0603≥2.2μF; 0805≥10μF;1206≥10μF</td></tr>
<tr><td>35V: 0603≥1μF;</td></tr>
<tr><td>25V: 0201≥0.1μF; 0402≥2.2μF;0603≥10μF; 0805≥10μF;1206≥22μF</td></tr>
<tr><td>16V: 0603≥10μF; 0402≥1μF; 0201≥0.22μF</td></tr>
<tr><td>10V: 0201>0.1μF; 0402≥1μF; 0603≥10μF; 0805≥47μF</td></tr>
<tr><td>6.3V:0201≥0.1μF;0402≥1μF;0603>4.7μF;0805≥47μF;1206≥10μF</td></tr>
</table></td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200 Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>14</td><td>Thermal Shock
MIL-STD-202
Method 107</td><td>* Conduct 300 cycles according to the temperatures and time.
<table>
<tr><th>Step</th><th>Temp. (℃)</th><th>Time (min.)</th></tr>
<tr><td>1</td><td>-55℃ +0/-3</td><td>15±3</td></tr>
<tr><td>2</td><td>+125℃ +3/-0</td><td>15±3</td></tr>
</table>
* Max. transfer time: 20 sec.
* Before initial measurement (X7R only): Perform 150+0/-10℃ for 1 hr and then set for 24±2 hrs at room temp.
* Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>* No remarkable damage.
* Cap change：NPO: within ±2.5% or 0.25pF whichever is larger
X7R: within ±10.0%
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F.≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦7.5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦20%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦3%</td><td>≦6%</td><td>0201(50V);0603≧0.047μF;0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.01uF;1210≧4.7μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.012μF;0603>0.1μF; 0805/X7R>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦5%</td><td>≦20%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦5%</td><td>≦10%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦14%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td>≦20%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0603≧0.15μF;0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.022μF;0402≧0.033μF;
0603>0.47μF;0805≧2.2μF;1206≧4.7μF;1210≧22μF</td></tr>
<tr><td rowspan="3">10V</td><td rowspan="3">≦7.5%</td><td>≦15%</td><td>0201≧0.012μF;0402≧0.22μF;
0603≧0.33μF;0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦20%</td><td>0201≧0.1μF;0402≧1μF</td></tr>
<tr><td>6.3V</td><td>≦15%</td><td>≦30%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF;1206≧47μF;1210≧100μF</td></tr>
<tr><td>4V</td><td>≦20%</td><td>---</td><td>---</td></tr>
</table>
* I.R.: ≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">1GΩ or RxC≧10 Ω-F whichever is smaller.</td></tr>
<tr><td>50V: 0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0603≥1μF;0805≥2.2μF; 1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0201≧0.1uF; 0402≥0.22μF; 0603≥2.2μF;0805≥2.2μF;
1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≧0.1uF;0402≥0.22μF;0603≥1μF;0805≥2.2μF;
1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
</table></td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200
Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>15.</td><td>ESD
AEC-Q200-002</td><td>Per AEC-Q200-002</td><td>
* No remarkable damage.
* Cap.: within the specified tolerance.
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F. ≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦10%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>0201(50V); 0603≧0.047μF; 0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0201≧0.01uF; 1210≧3.3μF</td></tr>
<tr><td>≦10%</td><td>0402≧0.012μF;0603>0.1μF; 0805>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦3.5%</td><td>≦10%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦7%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF; 1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td>≦12.5%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0402≧0.033μF;0603≧0.15μF;
0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.022μF; 0402≧ 0.22uF;0603>0.47μF;
0805≧2.2μF;1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0201≧0.012μF;0402≧0.22μF;0603≧0.33μF;
0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧1μF</td></tr>
<tr><td rowspan="2">6.3V</td><td rowspan="2">≦10%</td><td>≦15%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF; 1206≧47μF :1210≧100μF</td></tr>
<tr><td>≦20%</td><td>0402≧2.2μF</td></tr>
<tr><td>4V</td><td>≦15%</td><td>---</td><td>---</td></tr>
</table>
* I.R.: ≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="6">10GΩ or RxC≥100 Ω-F whichever is smaller.</td></tr>
<tr><td>50V: 0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0402≥1μF;0603≥2.2μF;0805≥2.2μF;1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≥0.1μF;0402≥0.22μF;0603≥1μF;
0805≥2.2μF;1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
1206≥4.7μF;1210≥47μF
6.3V ; 4V</td></tr>
</table>
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: 1210≥3.3μF</td><td rowspan="8">RxC≥50 Ω-F.</td></tr>
<tr><td>50V: 0402≥0.1μF; 0603≥2.2μF; 0805≥10μF;1206≥10μF</td></tr>
<tr><td>35V: 0603≥1μF;</td></tr>
<tr><td>25V: 0201≥0.1μF; 0402≥2.2μF;0603≥10μF; 0805≥10μF;1206≥22μF</td></tr>
<tr><td>16V: 0603≥10μF; 0402≥1μF; 0201≥0.22μF</td></tr>
<tr><td>10V: 0201>0.1μF; 0402≥1μF; 0603≥10μF; 0805≥47μF</td></tr>
<tr><td>6.3V:0201≥0.1μF;0402≥1μF;0603>4.7μF;0805≥47μF;1206≥10μF</td></tr>
<tr><td>4V:0603≥22μF; 0805≥47μF; 1206≥100μF</td></tr>
</table>
</td></tr>
<tr><td>16.</td><td>Solderability
J-STD-002
JESD22-B102E</td><td>* Condition A
Un-mounted chips 4hrs / 155°C*dry then completely immersed for 5±0.5 sec in solder bath at 235±5°C.
* Condition B
Un-mounted chips steam 8 hrs then completely immersed for 10±1sec in solder bath at 215+5/-0°C.
* Condition C
Un-mounted chips steam 8 hrs then completely immersed for 10±1 sec. in solder bath at 260+0/-5°C.</td><td>All terminations shall exhibit a continuous solder coating free from defects from a minimum of 95% of the critical surface area of any individual termination.</td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200
Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>17.</td><td>Electrical
Characterization</td><td>* Capacitance
* Q/ D.F. (Dissipation Factor)
*Test temp.: Room Temperature.
Class I: (NP0)
Cap≤1000pF 1.0±0.2Vrms, 1MHz±10%
Cap>1000pF 1.0±0.2Vrms, 1KHz±10%
Class II: (X7R)
Cap ≤10μF, 1.0±0.2Vrms，1KHz±10%
Cap＞10μF, 0.5±0.2Vrms，120Hz±20%</td><td>* Capacitance within the specified tolerance.
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F. ≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦10%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="3">50V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>0201(50V); 0603≧0.047μF; 0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0201≧0.01uF; 1210≧3.3μF</td></tr>
<tr><td>≦10%</td><td>0402≧0.012μF;0603>0.1μF; 0805>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>35V</td><td>≦3.5%</td><td>≦10%</td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦7%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF; 1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td>≦12.5%</td><td>0402≧0.47μF</td></tr>
<tr><td rowspan="2">16V</td><td rowspan="2">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0402≧0.033μF;0603≧0.15μF;
0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.022μF; 0402≧ 0.22uF;0603>0.47μF;
0805≧2.2μF;1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0201≧0.012μF;0402≧0.22μF;0603≧0.33μF;
0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧1μF</td></tr>
<tr><td>6.3V</td><td>≦10%</td><td>15%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF; 1206≧47μF :1210≧100μF</td></tr>
<tr><td>4V</td><td>≦15%</td><td>≦20%</td><td>0402≧2.2μF</td></tr>
</table></td></tr>
<tr><td></td><td></td><td>* Insulation Resistance
*Test temp.: Room Temperature.
To apply rated voltage(500V max.) for max. 120 sec.</td><td> IR. ≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II (X7R)
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: All X7R</td><td rowspan="7">10GΩ or RxC≥100 Ω-F whichever is smaller.</td></tr>
<tr><td>50V:0402>0.01μF;0603≥1μF;0805≥1μF;1206≥4.7μF;1210≥4.7μF</td></tr>
<tr><td>35V:0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td>25V:0402≥1μF;0603≥2.2μF;0805≥2.2μF;1206≥10μF;1210≥10μF</td></tr>
<tr><td>16V: 0201≥0.1μF 0402≥0.22μF;0603≥1μF;
0805≥2.2μF;1206≥10μF;1210≥47μF</td></tr>
<tr><td>10V:0201≥47nF;0402≥0.47μF;0603≥0.47μF;0805≥2.2μF;
4.7μF;1210 47μF</td></tr>
<tr><td>6.3V ; 4V</td></tr>
</table>
<table>
<tr><th>Rated voltage</th><th>Insulation Resistance</th></tr>
<tr><td>100V: 1210≥3.3μF</td><td rowspan="9">RxC≥50 Ω-F.</td></tr>
<tr><td>50V: 0402≥0.1μF; 0603≥2.2μF; 0805≥10μF;1206≥10μF</td></tr>
<tr><td>35V: 0603≥1μF;</td></tr>
<tr><td>25V: 0201≥0.1μF; 0402≥2.2μF;0603≥10μF; 0805≥10μF;1206≥22μF</td></tr>
<tr><td>16V: 0603≥10μF; 0402≥1μF; 0201≥0.22μF</td></tr>
<tr><td>10V: 0201>0.1μF; 0402≥1μF; 0603≥10μF; 0805≥47μF</td></tr>
<tr><td>6.3V:0201≥0.1μF;0402≥1μF;0603>4.7μF;0805≥47μF;1206≥10μF</td></tr>
<tr><td>4V:0603≥22μF; 0805≥47μF; 1206≥100μF</td></tr>
</table></td></tr>
<tr><td></td><td></td><td>* Dielectric Strength
To apply voltage:
≦100 ≥2.5 times VDC
200V~300V ≥2 times VDC
400V~450V ≥1.2 times VDC
500V~999V ≥1.5 times VDC
1000V~3000V ≥1.2 times VDC
, duration 1~5 sec,
charge and discharge current less than 50mA.</td><td>* Dielectric strength
No evidence of damage or flash over during test.</td></tr>
<tr><td></td><td></td><td>* Temperature Coefficient (with no electrical load)
Operation temperature: -55~125℃ at 25℃</td><td>* Temperature Coefficient
Capacitance Change: NPO: Within ±30ppm/℃
X7R: Within ±15%</td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

<table>
<tr><th>No.</th><th>AEC-Q200
Test Item</th><th>AEC-Q200 Test Condition</th><th>Requirements</th></tr>
<tr><td>18.</td><td>Board Flex
AEC-Q200-005</td><td>* The middle part of substrate shall be pressurized by means of the pressurizing rod at a rate of about 1 mm per second until the deflection becomes 5 mm and then the pressure shall be maintained for 60±1 sec.
* Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>* No remarkable damage.
* Cap change： NPO: within ±5% or 0.5pF whichever is larger
X7R: within ±12.5%
(This capacitance change means the change of capacitance under specified flexure of substrate from the capacitance measured before the test.)</td></tr>
<tr><td>19.</td><td>Terminal Strength
AEC-Q200-006</td><td>* Pressurizing force：2N (0201 & 0402), 10N(0603), 18N(≧0805).
* Test time: 60±1 sec.

35V ≦3.5% ≦10%</td><td>* No remarkable damage or removal of the terminations.
* Capacitance within the specified tolerance.
* Q/D.F. value:
NPO: Cap≥30pF, Q≥1000 ; Cap<30pF, Q≥400+20C.
X7R:
<table>
<tr><th>Rated vol.</th><th>D.F.≦</th><th colspan="2">Exception of D.F. ≦</th></tr>
<tr><td rowspan="3">≧100V</td><td rowspan="3">≦2.5%</td><td>≦3%</td><td>1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0603≧0.068μF;0805＞0.1μF;1206≧1μF;1210≧2.2μF</td></tr>
<tr><td>≦10%</td><td>0805＞0.22μF;1210≧3.3μF</td></tr>
<tr><td rowspan="4">50V</td><td rowspan="4">≦2.5%</td><td>≦3%</td><td>0201(50V); 0603≧0.047μF; 0805≧0.18μF;1206≧0.47μF</td></tr>
<tr><td>≦5%</td><td>0201≧0.01uF; 1210≧3.3μF</td></tr>
<tr><td>≦10%</td><td>0402≧0.012μF;0603>0.1μF; 0805>0.47μF;
1206≧2.2μF;1210≧10μF</td></tr>
<tr><td></td><td>0603≧1μF;0805≥2.2μF;1206≧2.2μF;1210≧10μF</td></tr>
<tr><td rowspan="4">25V</td><td rowspan="4">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0805≧1μF;1210≧10μF</td></tr>
<tr><td>≦7%</td><td>0603≧0.33μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.1μF; 0402≧0.056μF;0603≧0.47μF;
0805≧2.2μF; 1206≧4.7μF; 1210≧22μF</td></tr>
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<tr><td rowspan="2">16V</td><td rowspan="2">≦3.5%</td><td>≦5%</td><td>0201≧0.01μF;0402≧0.033μF;0603≧0.15μF;
0805≧0.68μF;1206≧2.2μF;1210≧4.7μF</td></tr>
<tr><td>≦10%</td><td>0201≧0.022μF; 0402≧ 0.22uF;0603>0.47μF;
0805≧2.2μF;1206≧4.7μF; 1210≧22μF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≦5%</td><td>≦10%</td><td>0201≧0.012μF;0402≧0.22μF;0603≧0.33μF;
0805≧2.2μF;1206≧2.2μF;1210≧22μF</td></tr>
<tr><td>≦15%</td><td>0201≧0.1μF; 0402≧1μF</td></tr>
<tr><td rowspan="2">6.3V</td><td rowspan="2">≦10%</td><td>≦15%</td><td>0201≧0.1μF;0402≧1μF;0603≧10μF;
0805≧4.7μF; 1206≧47μF :1210≧100μF</td></tr>
<tr><td>≦20%</td><td>0402≧2.2μF</td></tr>
<tr><td>4V</td><td>≦15%</td><td>---</td><td>---</td></tr>
</table></td></tr>
<tr><td>20</td><td>Beam Load Test
AEC-Q200-003</td><td>* Break strength test
* Beam speed: 2.5±0.25 mm/sec</td><td>The chip endure following force
* Chip length 2.5mm: Thickness >0.5mm (20N), ≤0.5mm (8N)
* Chip length ≥3.2mm: Thickness ≥1.25mm (54.5N), <1.25mm (15N)</td></tr>
</table>

* "Room condition" Temperature: 15 to 35℃, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

APPENDIXES

◙ Tape & reel dimensions

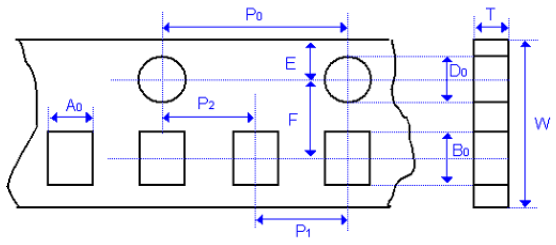

Fig. 2 The dimension of paper tape

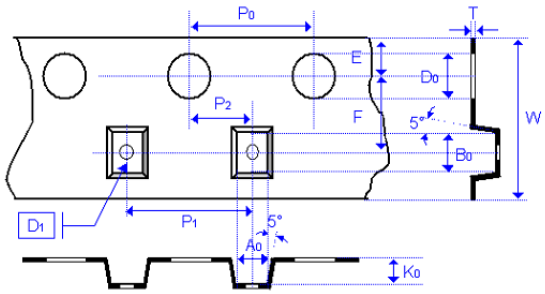

Fig. 3 The dimension of plastic tape

Size	0603	0805			1206			1210		
Thickness	S,H,X	A,H	B,T	D,I	B,T	C,J,D	G,P	T	C,D,G,K	M
A_0	1.05 +/-0.30	1.50 +/-0.20	1.50 +/-0.20	≦1.80	1.90 +/-0.50	< 2.00	<2.30	< 3.05	< 3.05	< 3.20
B_0	1.80 +/-0.30	2.30 +/-0.20	2.30 +/-0.20	< 2.70	3.50 +/-0.50	< 3.70	< 4.00	< 3.80	< 3.80	<4.00
T	≦1.20	≦1.15	≦1.20	0.23 +/-0.1	≦1.20	0.23 +/-0.1	0.23 +/-0.1	0.23 +/-0.1	0.23 +/-0.1	0.23 +/-0.1
K_0	-	-	-	< 2.50	-	< 2.50	< 2.50	< 1.50	< 2.50	< 3.50
W	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30
P_0	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
$10xP_0$	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20
P_1	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
P_2	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05
D_0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0
D_1	-	-	-	-	-	-	-	1.00 +/-0.10	1.00 +/-0.10	1.00 +/-0.10
E	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10
F	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05

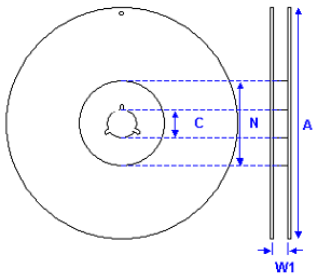

Fig. 4 The dimension of reel

Size	0201, 0402, 0603, 0805, 1206, 1210		
Reel size	7”	10”	13”
C	13.0±0.5	13.0±0.5	13.0±0.5
W_1	10.0±1.5	10.0±1.5	10.0±1.5
A	178.0±2.0	250.0±2.0	330.0±2.0
N	60.0+1.0/-0	50 min	50 min

◙ Constructions

No.	Name		X7R
①	Ceramic material		$BaTiO_3$ based
②	Inner electrode		Ni
③	Termination	Inner layer	Cu + Conductive Resin
④		Middle layer	Ni
⑤		Outer layer	Sn (Matt)

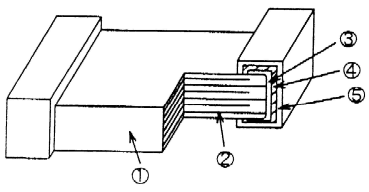

Fig. 5 The construction of MLCC

◙ Storage and handling conditions

(1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions; MSL Level 1.

(2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

Cautions:

a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)

b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.

c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight,the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.

◙ Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of N_2 within oven are recommended.

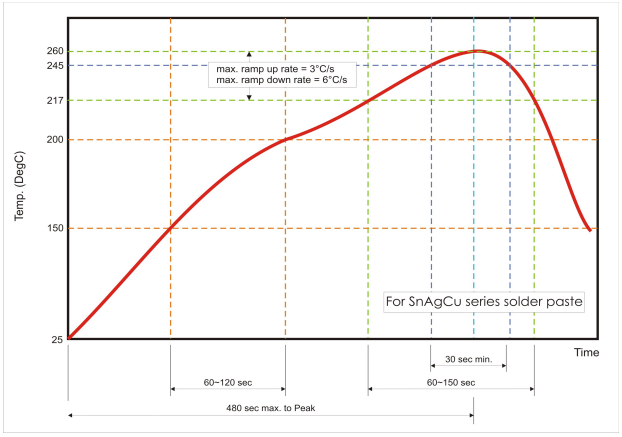

Fig. 5 Recommended reflow soldering profile for SMT process with SnAgCu series solder paste.

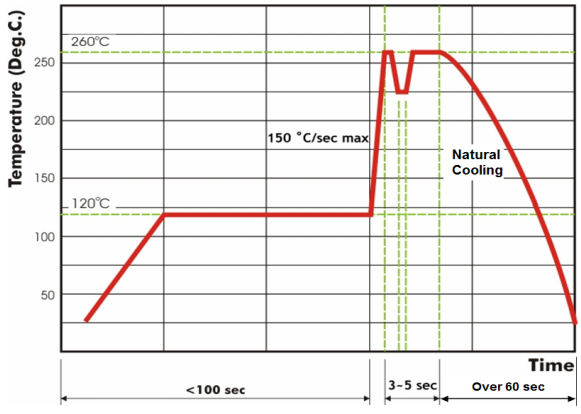

Fig. 6 Recommended wave soldering profile for SMT process with SnAgCu series solder.